GR 99 P 1058

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Wilfried Daehn

Appl. No. : 09/484,781

Filed : January 18, 2000

Title : Integrated Semiconductor Circuit and Method for Functional Testing of Pad Cells

Examiner : Don Le

Group Art Unit : 2819

A M E N D M E N T

Hon. Commissioner of Patents and Trademarks
Washington, DC 20231

S i r :

Responsive to the Office action dated July 2, 2001, kindly amend the above-identified application as follows:

In the Claims:

Cancel claim 4.

Claim 1 (amended). An integrated semiconductor circuit, comprising: